

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
		"AC Interconnect Test With Series Boundary Scan", P.K. Graham, IBM Technical Disclosure Bulletin	IBM_TDB	OR	ON	2005/05/17 15:13
		"AC Interconnect Test With Series Boundary Scan", P.K. Graham, IBM Technical Disclosure Bulletin	IBM_TDB	OR	ON	2005/05/17 15:13
S1	0	("AC_Extest" "AC_Extest" (AC near Extest))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/26 14:22
S2	0	("AC_EXTEST" "AC_EXTEST" (AC near Extest))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/08/11 13:50
S3	63	("AC" AND Extest) and (IEEE "1149.1")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/08/11 13:51
S4	8	((AC" and Extest) and (IEEE "1149.1") and "boundary scan cell" and controller)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/08/11 13:53
S5	387851	((AC" and Extest) and (IEEE "1149.1") and boundary scan cell and controller)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/08/11 13:53
S6	55	((AC" and Extest) and (IEEE "1149.1") and (boundary scan cell) and controller)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/08/11 13:53
S7	63	"AC" AND Extest	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/08/12 13:04
S8	290	(AC near\$3 Extest) and (boundary near scan near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/08/12 13:11

S9	9	((AC near\$3 Extest) and (boundary near scan near test\$3)).ti. ((AC near\$3 Extest) and (boundary near scan near test\$3)).ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/08/12 13:12
S10	15	((AC near\$3 Extest) and (boundary near scan near test\$3)).ti. ((AC near\$3 Extest) and (boundary near scan near test\$3)).ab.((AC near\$3 Extest) and (boundary near scan near test\$3)).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/08/12 13:13
S11	25	((AC near\$3 Extest) and (boundary near scan near test\$3)) and (AC near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/08/12 13:13
S12	2707699	(test\$3) near\$2 (AC near (interconnect\$4 connect\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/15 15:23
S13	26	(test\$3) near ("AC" near (interconnect\$4 connect\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/03/15 15:47
S14	0	"834506"	US-PGPUB	OR	ON	2004/03/15 15:47
S15	3	(test\$3) near ("AC") near interconnects	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/20 15:28
S16	1019	(test\$3) near interconnects	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/20 15:28
S17	59	(test\$3) near interconnects near circuit	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/20 15:35
S18	18	((test\$3) near interconnects near circuit) and (boundary near scan)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/20 15:52
S19	114	quantum near processing	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/26 14:22

S20	9	("quantum processing").ab.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/26 14:23
S21	53	"quantum processing"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/26 14:24
S22	2	"quantum processing".ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/27 11:07
S23	622	(boundary near scan near test\$3) and (interconnect\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/27 11:08
S24	137	(boundary near scan near test\$3) with (interconnect\$4)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/27 11:09
S25	57	(boundary near scan near test\$3) with (interconnect\$4 near test\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/27 11:14
S26	0	(boundary near scan near test\$3) with (interconnect\$4 near test\$3 near ("AC" "DC"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/27 11:15
S27	10	(interconnect\$4 near test\$3 near ("AC" "DC"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/05/27 11:15
S28	2494	(test\$3 near (AC interconnect))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/17 14:55
S29	2736	(test\$3 near (AC interconnect))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/17 14:55

S30	11	(test\$3 near ("AC interconnect"))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/17 15:09
S31	13	(test\$3 with AC with interconnect with scan with boundary)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/17 15:13
S32	15	(test\$3 with AC with interconnect with scan)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/17 15:10
S33	0	"AC Interconnect Test With Series Boundary Scan"	IBM_TDB	OR	ON	2005/05/17 15:13
S34	5220	""AC Interconnect Test With Series Boundary Scan", P.K. Graham, IBM Technical Disclosure Bulletin"	IBM_TDB	OR	ON	2005/05/17 15:14
S35	0	"AC Interconnect Test With Series Boundary Scan"	IBM_TDB	OR	ON	2005/05/17 15:17
S36	2	(AC with Interconnect with test\$3)	IBM_TDB	OR	ON	2005/05/17 15:17
S37	75	(AC with Interconnect with test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/17 15:19
S40	2239	(AC with test\$3).ab.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/17 15:20
S41	1006	(AC with test\$3).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/17 15:20
S42	5	(AC with Interconnect with test\$3).ti.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/18 09:24
S43	13	(AC with Interconnect with test\$3).ab.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/18 09:13

S44	23	(AC with Interconnect with test\$3) and (capac\$6 farad coulomb accumulator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/18 09:26
S45	24	(AC with Interconnect with test\$3) and (capac\$7 farad coulomb accumulator)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/18 12:49
S46	75	(AC with Interconnect with test\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/18 12:49
S47	6	(AC with Interconnect with test\$3) and (boundary near scan) and (tap with (run test idle))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT	OR	ON	2005/05/18 12:50